



72nd
International
Electron
Devices
Meeting

Devices at the Heart of the Intelligence Revolution

2026 International
Electron Devices
Meeting

December 12-16, 2026

Hilton San Francisco Union Square
San Francisco, CA

IEDM is pleased to announce increased
technical focus in the area of:

RELIABILITY OF SYSTEMS and DEVICES (RSD)

Topics

Papers are solicited in the following themes of interest:

- Component-level FEOL/MOL/BEOL characterization and reliability modeling
- Reliability of conventional and emerging memories
- Circuits, systems-level reliability, and aging
- Thermal and PID/charging management in existing and novel process integration
- Reliability of RF/mm-wave/5G in high-frequency applications
- Reliability of devices, circuits, and systems for more-than-Moore applications, automotive, aerospace and bio-applications (BioFETs, DNA detection, etc.)
- Reliability of cryogenic devices for future quantum computing applications

New or trending areas include:

- Reliability of new materials and/or new architectures for transistors
- Reliability of advanced 2.5D/3D IC advanced package
- Design for testing (DFT) / Design for reliability (DFR) solutions for improved reliability
- Robustness and security of electronic circuits and systems

Paper Submission

Deadline: July 16th

Single submission of final, four-page paper



For More Information

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